

**PATENT NUMBER and
ISSUE DATE**

U.S. UTILITY Patent Application

APPL NUM 10002000	FILING DATE 12/05/2001	CLASS 252 350	SUBCLASS C.1	GALV 2872	EXAMINER BARTH
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****CONTINUING DATA VERIFIED:**

** FOREIGN APPLICATIONS VERIFIED:
JAPAN 2000-372456 12/07/2000

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiners's initials		<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO 011593
TITLE : Axis determination apparatus, film-thickness measurement apparatus, deposition apparatus, axis determination method, and film-thickness measurement method			
U.S. DEPT. OF COMM./PAT. & TM-PTO-4361 (Rev. 12-61)			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.	Print Fig.
<input type="checkbox"/> TERMINAL	PREPARED FOR ISSUE			Application Examiner
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